

**Notice of References Cited**

Application/Control No.

10/682,542

Applicant(s)/Patent Under  
Reexamination  
WEE ET AL.

Examiner

X. L. Bautista

Art Unit

2179

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,106,358 B2	09-2006	Valliath et al.	348/14.08
*	B	US-6,307,952 B1	10-2001	Dietz, Paul H.	382/107
*	C	US-6,256,046 B1	07-2001	Waters et al.	345/473
*	D	US-2003/0208289 A1	11-2003	Ben-Arie, Jezekiel	700/61
*	E	US-6,215,890 B1	04-2001	Matsuo et al.	382/103
*	F	US-2003/0112139 A1	06-2003	Matsui et al.	340/500
*	G	US-6,081,619	06-2000	Hashimoto et al.	382/181
*	H	US-6,801,637 B2	10-2004	Voronka et al.	382/103
*	I	US-2004/0133081 A1	07-2004	Teller et al.	600/300
*	J	US-6,428,449 B1	08-2002	Apseloff, Stanford	482/3
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.